**Preferred Device** 

# Power MOSFET 6 Amps, 20 Volts

### P-Channel SOIC-8, Dual

#### **Features**

- Ultra Low R<sub>DS(on)</sub>
- Higher Efficiency Extending Battery Life
- Logic Level Gate Drive
- Miniature Dual SOIC-8 Surface Mount Package
- Diode Exhibits High Speed, Soft Recovery
- Avalanche Energy Specified
- SOIC–8 Mounting Information Provided
- Pb-Free Packages are Available

#### **Applications**

• Power Management in Portable and Battery–Powered Products, i.e.: Cellular and Cordless Telephones, and PCMCIA Cards

#### **MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Drain-to-Source Voltage	$V_{DSS}$	-20	V
Gate-to-Source Voltage - Continuous	V <sub>GS</sub>	±12	V
Thermal Resistance – Junction-to-Ambient (Note 1) Total Power Dissipation @ T <sub>A</sub> = 25°C Continuous Drain Current @ T <sub>A</sub> = 25°C Continuous Drain Current @ T <sub>A</sub> = 70°C Maximum Operating Power Dissipation Maximum Operating Drain Current Pulsed Drain Current (Note 4)	R <sub>θJA</sub> P <sub>D</sub> I <sub>D</sub> I <sub>D</sub> I <sub>D</sub> I <sub>DM</sub>	62.5 2.0 -7.8 -5.7 0.5 -3.89 -40	°C/W W A A W A
Thermal Resistance – Junction–to–Ambient (Note 2) Total Power Dissipation @ $T_A = 25^{\circ}C$ Continuous Drain Current @ $T_A = 25^{\circ}C$ Continuous Drain Current @ $T_A = 70^{\circ}C$ Maximum Operating Power Dissipation Maximum Operating Drain Current Pulsed Drain Current (Note 4)	R <sub>0</sub> JA P <sub>D</sub> I <sub>D</sub> I <sub>D</sub> I <sub>D</sub> I <sub>DM</sub>	98 1.28 -6.2 -4.6 0.3 -3.01 -35	°C/W W A A W A
Thermal Resistance – Junction–to–Ambient (Note 3) Total Power Dissipation @ T <sub>A</sub> = 25°C Continuous Drain Current @ T <sub>A</sub> = 25°C Continuous Drain Current @ T <sub>A</sub> = 70°C Maximum Operating Power Dissipation Maximum Operating Drain Current Pulsed Drain Current (Note 4)	R <sub>θJA</sub> P <sub>D</sub> I <sub>D</sub> I <sub>D</sub> I <sub>D</sub> I <sub>DM</sub>	166 0.75 -4.8 -3.5 0.2 -2.48 -30	°C/W W A A W A
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Single Pulse Drain-to-Source Avalanche Energy – Starting $T_J = 25^{\circ}C$ ( $V_{DD} = -20$ Vdc, $V_{GS} = -5.0$ Vdc, Peak $I_L = -5.0$ Apk, $L = 40$ mH, $R_G = 25$ $\Omega$ )	E <sub>AS</sub>	500	mJ
Maximum Lead Temperature for Soldering Purposes for 10 seconds	TL	260	°C

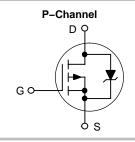
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



#### ON Semiconductor®

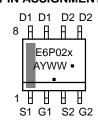
http://onsemi.com

#### 6 AMPERES, 20 VOLTS



## MARKING DIAGRAM & PIN ASSIGNMENT





E6P02 = Specific Device Code

x = Blank or S

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMD6P02R2	SOIC-8	2500 / Tape & Reel
NTMD6P02R2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel
NTMD6P02R2SG	SOIC-8 (Pb-Free)	2500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

**Preferred** devices are recommended choices for future use and best overall value.

- 1. Mounted onto a 2" square FR-4 Board (1 in sq. 2 oz. Cu 0.06" thick single sided), t = 10 seconds.
- 2. Mounted onto a 2" square FR-4 Board (1 in sq, 2 oz. Cu 0.06" thick single sided), t = steady state.
- 3. Minimum FR-4 or G-10 PCB, t = steady state.
- 4. Pulse Test: Pulse Width = 300 μs, Duty Cycle = 2%.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)\*

Characteristic			Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage			20			Vdc
(V <sub>GS</sub> = 0 Vdc, I <sub>D</sub> = -250 μAdc) Temperature Coefficient (Positive)			–20 –	-11.6	_	mV/°C
Zero Gate Voltage Drain Current						μAdc
$(V_{DS} = -20 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T_J = 25^{\circ}\text{C})$ $(V_{DS} = -20 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T_J = 70^{\circ}\text{C})$			_	_	-1.0 -5.0	
Gate–Body Leakage Current (V <sub>GS</sub> = -12 Vdc, V <sub>DS</sub> = 0 Vdc)			_	_	-100	nAdc
Gate–Body Leakage Current (V <sub>GS</sub> = +12 Vdc, V <sub>DS</sub> = 0 Vdc)			_	_	100	nAdc
ON CHARACTERISTICS					100	
Gate Threshold Voltage		V <sub>GS(th)</sub>				Vdc
Gate Threshold Voltage $(V_{DS} = V_{GS}, I_D = -250 \mu Adc)$			-0.6	-0.88	-1.20	
Temperature Coefficient (Negative)			_	2.6	-	mV/°C
Static Drain-to-Source On-State R ( $V_{GS} = -4.5 \text{ Vdc}$ , $I_D = -6.2 \text{ Adc}$ )	esistance	R <sub>DS(on)</sub>	_	0.027	0.033	Ω
$(V_{GS} = -2.5 \text{ Vdc}, I_D = -5.0 \text{ Adc})$			_	0.038	0.050	
$(V_{GS} = -2.5 \text{ Vdc}, I_D = -3.1 \text{ Adc})$	40 \/d= 1	_	_	0.038	_	Mhaa
Forward Transconductance (V <sub>DS</sub> =	-10 vac, I <sub>D</sub> = -6.2 Aac)	9FS	_	15	_	Mhos
Input Capacitance	I	C	_	1380	1700	nE
· · · ·	$(V_{DS} = -16 \text{ Vdc}, V_{GS} = 0 \text{ Vdc},$	Ciss		515	775	pF -
Output Capacitance  Reverse Transfer Capacitance	f = 1.0 MHz)	Coss		250		
•	1	C <sub>rss</sub>	_	250	450	
SWITCHING CHARACTERISTICS ( Turn-On Delay Time	Notes 5 and 6)	t., ,	_	15	25	ns
Rise Time	$(V_{DD} = -10 \text{ Vdc}, I_D = -1.0 \text{ Adc},$	t <sub>d(on)</sub>		20	50	- 115
Turn-Off Delay Time	$V_{GS} = -10 \text{ Vdc},$	-		85	125	<u> </u>
Fall Time	$R_G = 6.0 \Omega$ )	t <sub>d(off)</sub>	-	50		
		t <sub>f</sub>	_		110	no
Turn-On Delay Time	$(V_{DD} = -16 \text{ Vdc}, I_D = -6.2 \text{ Adc},$	t <sub>d(on)</sub>	_	17	-	ns
Rise Time	$V_{GS} = -4.5 \text{ Vdc},$	t <sub>r</sub>	_	65	_	
Turn-Off Delay Time	$R_G = 6.0 \Omega$ )	t <sub>d(off)</sub>	_	50	_	_
Fall Time		t <sub>f</sub>	_	80	-	
Total Gate Charge	$(V_{DS} = -16 \text{ Vdc},$	Q <sub>tot</sub>	_	20	35	nC
Gate-Source Charge	$V_{GS} = -4.5 \text{ Vdc},$ $I_{D} = -6.2 \text{ Adc})$	Q <sub>gs</sub>	-	4.0	_	_
Gate-Drain Charge		$Q_{gd}$	_	8.0	_	
BODY-DRAIN DIODE RATINGS (N	· ·				T	T
Diode Forward On–Voltage	$(I_S = -1.7 \text{ Adc}, V_{GS} = 0 \text{ Vdc})$ $(I_S = -1.7 \text{ Adc}, V_{GS} = 0 \text{ Vdc}, T_J = 125^{\circ}\text{C})$	V <sub>SD</sub>	-	-0.80 -0.65	-1.2 -	Vdc
Diode Forward On–Voltage	$(I_S = -6.2 \text{ Adc}, V_{GS} = 0 \text{ Vdc})$ $(I_S = -6.2 \text{ Adc}, V_{GS} = 0 \text{ Vdc}, T_J = 125^{\circ}\text{C})$	V <sub>SD</sub>	1 1	-0.95 -0.80	_ _	Vdc
Reverse Recovery Time	(I <sub>S</sub> = -1.7 Adc, V <sub>GS</sub> = 0 Vdc, dI <sub>S</sub> /dt = 100 A/μs)	t <sub>rr</sub>	-	50	80	ns
		t <sub>a</sub>	_	20	_	
	2.3.2. 100,4400)	t <sub>r</sub>	-	30	_	
Reverse Recovery Stored Charge			_	0.04	_	μС

<sup>5.</sup> Indicates Pulse Test: Pulse Width = 300 μs max, Duty Cycle = 2%.
6. Switching characteristics are independent of operating junction temperature.

<sup>\*</sup>Handling precautions to protect against electrostatic discharge are mandatory.

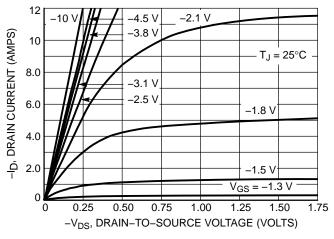


Figure 1. On-Region Characteristics

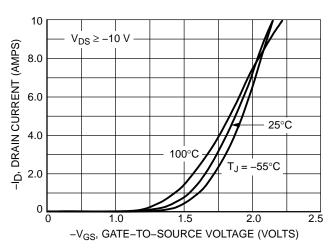


Figure 2. Transfer Characteristics

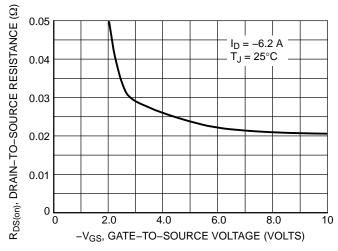


Figure 3. On–Resistance versus Gate–To–Source Voltage

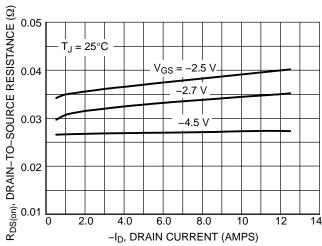


Figure 4. On-Resistance versus Drain Current and Gate Voltage

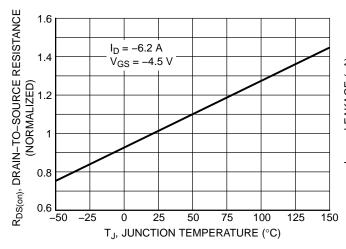


Figure 5. On–Resistance Variation with Temperature

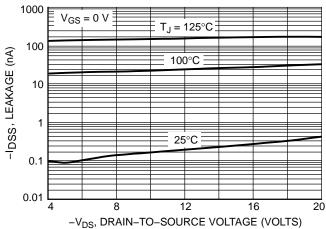
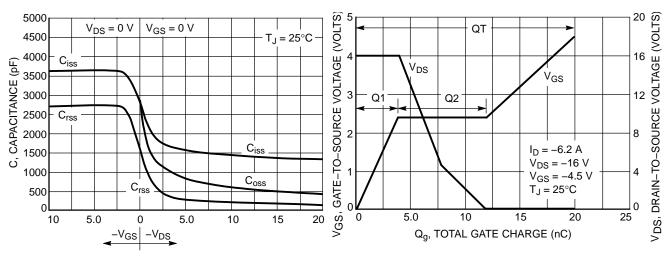


Figure 6. Drain-To-Source Leakage Current versus Voltage



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage versus Total Charge

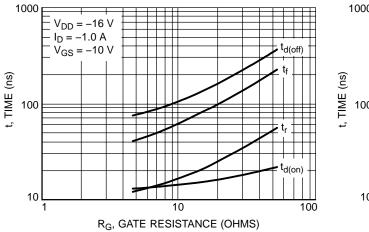


Figure 9. Resistive Switching Time Variation versus Gate Resistance

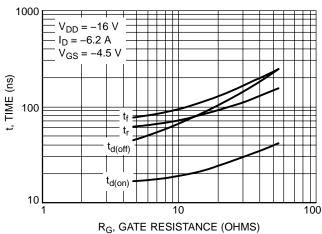


Figure 10. Resistive Switching Time Variation versus Gate Resistance

#### DRAIN-TO-SOURCE DIODE CHARACTERISTICS

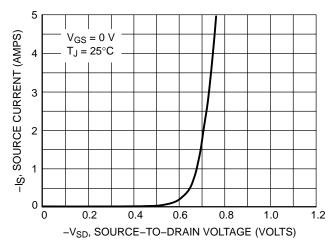


Figure 11. Diode Forward Voltage versus Current

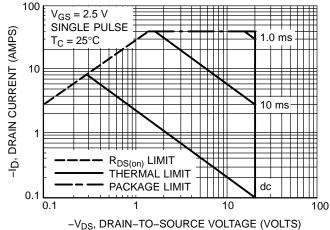


Figure 12. Maximum Rated Forward Biased Safe Operating Area

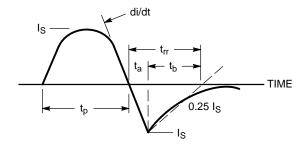


Figure 13. Diode Reverse Recovery Waveform

#### TYPICAL ELECTRICAL CHARACTERISTICS

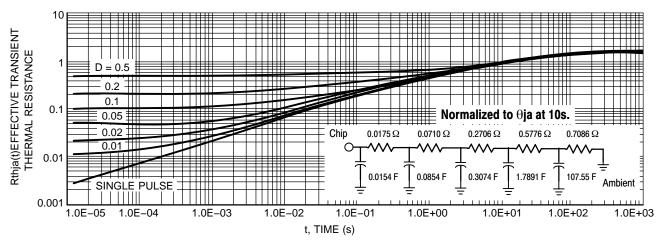
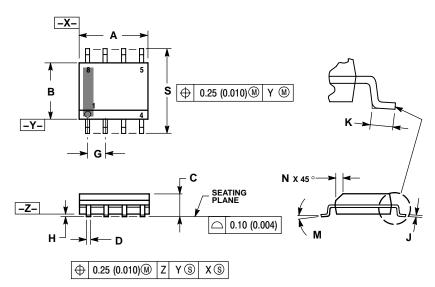


Figure 14. Thermal Response

#### PACKAGE DIMENSIONS

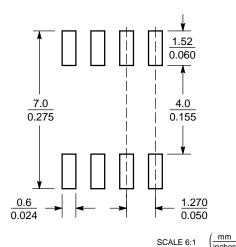
SOIC-8 NB CASE 751-07 **ISSUE AH** 



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27	7 BSC	0.05	0 BSC
Н	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
M	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

#### SOLDERING FOOTPRINT\*



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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